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Danbury et al.

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(54) **MEASUREMENT METHOD**

(56) **References Cited**

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(57) **ABSTRACT**

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(52) **U.S. Cl.**

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(58) **Field of Classification Search**

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See application file for complete search history.

A method of locating a feature of an object in which the method includes bringing a stylus of a contact probe mounted on a positioning apparatus into contact with the object to obtain at least first and second measurements of the object. Each which the measurements gives rise to a range of possible points of contact between the object and a part of the stylus along its length and therefore inherently containing uncertainty in the location of the object along said length. The at least first and second measurements are used to reduce the extent of said uncertainty which includes using stylus orientation related information associated with the at least first and second measurements.

16 Claims, 11 Drawing Sheets

